

<b>Notice of References Cited</b>	Application/Control No. 09/232,119	Applicant(s)/Patent Under Reexamination WEITZEL, THILO	
	Examiner David S. Kim	Art Unit 2633	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-3,469,923	09-1969	MERTZ LAWRENCE N	356/451
	B	US-3,482,919	12-1969	BARRINGER ANTHONY RENE	356/455
	C	US-4,190,366	02-1980	Doyle, Walter M.	356/455
	D	US-4,533,247	08-1985	Epworth, Richard E.	356/479
	E	US-5,073,331	12-1991	Shirasaki, Masataka	372/26
	F	US-5,351,124	09-1994	Laskoskie et al.	356/477
	G	US-5,412,474	05-1995	Reasenberg et al.	356/486
	H	US-6,104,517	08-2000	Blodgett et al.	398/201
	I	US-6,115,121	09-2000	Erskine, David J.	356/450
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Hecht, E. and A. Zajac. Optics. Reading, Massachusetts: Addison Wesley Publishing Company, Inc., 1974. p. 37-38, 62-65, 189-190, 286-290.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.